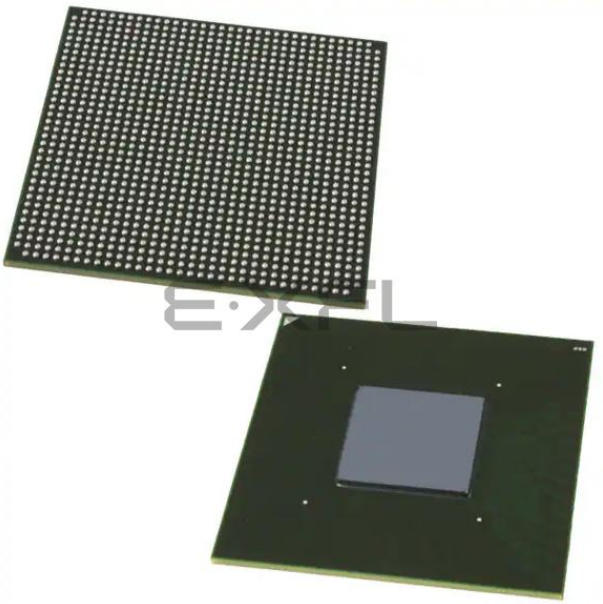

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Details	
Product Status	Obsolete
Number of LABs/CLBs	17110
Number of Logic Elements/Cells	362000
Total RAM Bits	19822592
Number of I/O	544
Number of Gates	-
Voltage - Supply	1.12V ~ 1.18V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1152-BBGA, FCBGA Exposed Pad
Supplier Device Package	1152-FBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5agtfd3h3f35i3n

Arria V GX, GT, SX, and ST Device Datasheet

1

2017.02.10

AV-51002

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This datasheet describes the electrical characteristics, switching characteristics, configuration specifications, and I/O timing for Arria® V devices.

Arria V devices are offered in commercial and industrial grades. Commercial devices are offered in –C4 (fastest), –C5, and –C6 speed grades. Industrial grade devices are offered in the –I3 and –I5 speed grades.

Related Information

Arria V Device Overview
Provides more information about the densities and packages of devices in the Arria V family.

Electrical Characteristics

The following sections describe the operating conditions and power consumption of Arria V devices.

Operating Conditions

Arria V devices are rated according to a set of defined parameters. To maintain the highest possible performance and reliability of the Arria V devices, you must consider the operating requirements described in this section.

Absolute Maximum Ratings

This section defines the maximum operating conditions for Arria V devices. The values are based on experiments conducted with the devices and theoretical modeling of breakdown and damage mechanisms.

The functional operation of the device is not implied for these conditions.

Symbol	Description	Condition	Minimum[7]	Typical	Maximum[7]	Unit
V_{CCPD_HPS} [8]	HPS I/O pre-driver power supply	3.3 V	3.135	3.3	3.465	V
		3.0 V	2.85	3.0	3.15	V
		2.5 V	2.375	2.5	2.625	V
V_{CCIO_HPS}	HPS I/O buffers power supply	3.3 V	3.135	3.3	3.465	V
		3.0 V	2.85	3.0	3.15	V
		2.5 V	2.375	2.5	2.625	V
		1.8 V	1.71	1.8	1.89	V
		1.5 V	1.425	1.5	1.575	V
		1.35 V [9]	1.283	1.35	1.418	V
		1.2 V	1.14	1.2	1.26	V
$V_{CCRSTCLK\_HPS}$	HPS reset and clock input pins power supply	3.3 V	3.135	3.3	3.465	V
		3.0 V	2.85	3.0	3.15	V
		2.5 V	2.375	2.5	2.625	V
		1.8 V	1.71	1.8	1.89	V
V_{CCPLL_HPS}	HPS PLL analog voltage regulator power supply	—	2.375	2.5	2.625	V

(7) The power supply value describes the budget for the DC (static) power supply tolerance and does not include the dynamic tolerance requirements. Refer to the PDN tool for the additional budget for the dynamic tolerance requirements.

(8) V_{CCPD_HPS} must be 2.5 V when V_{CCIO_HPS} is 2.5, 1.8, 1.5, or 1.2 V. V_{CCPD_HPS} must be 3.0 V when V_{CCIO_HPS} is 3.0 V. V_{CCPD_HPS} must be 3.3 V when V_{CCIO_HPS} is 3.3 V.

(9) V_{CCIO_HPS} 1.35 V is supported for HPS row I/O bank only.

I/O Pin Leakage Current

Table 1-6: I/O Pin Leakage Current for Arria V Devices

Symbol	Description	Condition	Min	Typ	Max	Unit
I_I	Input pin	V_I = 0 V to $V_{CCIOMAX}$	–30	—	30	µA
I_{OZ}	Tri-stated I/O pin	V_O = 0 V to $V_{CCIOMAX}$	–30	—	30	µA

Bus Hold Specifications

Table 1-7: Bus Hold Parameters for Arria V Devices

The bus-hold trip points are based on calculated input voltages from the JEDEC standard.

Parameter	Symbol	Condition	V_{CCIO} (V)												Unit
			1.2		1.5		1.8		2.5		3.0		3.3		
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Bus-hold, low, sustaining current	I_{SUSL}	$V_{IN} > V_{IL}$ (max)	8	—	12	—	30	—	50	—	70	—	70	—	µA
Bus-hold, high, sustaining current	I_{SUSH}	$V_{IN} < V_{IH}$ (min)	–8	—	–12	—	–30	—	–50	—	–70	—	–70	—	µA
Bus-hold, low, overdrive current	I_{ODL}	0 V < V_{IN} < V_{CCIO}	—	125	—	175	—	200	—	300	—	500	—	500	µA
Bus-hold, high, overdrive current	I_{ODH}	0 V < V_{IN} < V_{CCIO}	—	–125	—	–175	—	–200	—	–300	—	–500	—	–500	µA

I/O Standard	V_{CCIO} (V)			$V_{SWING(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{SWING(AC)}$ (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Max
SSTL-125	1.19	1.25	1.31	0.18	(15)	$V_{CCIO}/2 - 0.15$	$V_{CCIO}/2$	$V_{CCIO}/2 + 0.15$	$2(V_{IH(AC)} - V_{REF})$	$2(V_{IL(AC)} - V_{REF})$

Differential HSTL and HSUL I/O Standards

Table 1-18: Differential HSTL and HSUL I/O Standards for Arria V Devices

I/O Standard	V_{CCIO} (V)			$V_{DIF(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{CM(DC)}$ (V)			$V_{DIF(AC)}$ (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Typ	Max	Min	Max
HSTL-18 Class I, II	1.71	1.8	1.89	0.2	—	0.78	—	1.12	0.78	—	1.12	0.4	—
HSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	0.68	—	0.9	0.68	—	0.9	0.4	—
HSTL-12 Class I, II	1.14	1.2	1.26	0.16	$V_{CCIO} + 0.3$	—	$0.5 \times V_{CCIO}$	—	$0.4 \times V_{CCIO}$	$0.5 \times V_{CCIO}$	$0.6 \times V_{CCIO}$	0.3	$V_{CCIO} + 0.48$
HSUL-12	1.14	1.2	1.3	0.26	0.26	$0.5 \times V_{CCIO} - 0.12$	$0.5 \times V_{CCIO}$	$0.5 \times V_{CCIO} + 0.12$	$0.4 \times V_{CCIO}$	$0.5 \times V_{CCIO}$	$0.6 \times V_{CCIO}$	0.44	0.44

Differential I/O Standard Specifications

Table 1-19: Differential I/O Standard Specifications for Arria V Devices

Differential inputs are powered by V_{CCPD} which requires 2.5 V.

Symbol/Description	Condition	Transceiver Speed Grade 3			Unit
		Min	Typ	Max	
Transmitter REFCLK phase noise(43)	10 Hz	—	—	–50	dBc/Hz
	100 Hz	—	—	–80	dBc/Hz
	1 KHz	—	—	–110	dBc/Hz
	10 KHz	—	—	–120	dBc/Hz
	100 KHz	—	—	–120	dBc/Hz
	≥ 1 MHz	—	—	–130	dBc/Hz
R_{REF}	—	—	2000 ±1%	—	Ω

Table 1-27: Transceiver Clocks Specifications for Arria V GT and ST Devices

Symbol/Description	Condition	Transceiver Speed Grade 3			Unit
		Min	Typ	Max	
fixedclk clock frequency	PCIe Receiver Detect	—	125	—	MHz
Transceiver Reconfiguration Controller IP (mgmt_clk_clk) clock frequency	—	75	—	125	MHz

Table 1-28: Receiver Specifications for Arria V GT and ST Devices

Symbol/Description	Condition	Transceiver Speed Grade 3			Unit
		Min	Typ	Max	
Supported I/O Standards	1.5 V PCML, 2.5 V PCML, LVPECL, and LVDS				
Data rate (6-Gbps transceiver)(44)	—	611	—	6553.6	Mbps

(43) The transmitter REFCLK phase jitter is 30 ps p-p (5 ps RMS) with bit error rate (BER) 10^{-12}, equivalent to 14 sigma.
(44) To support data rates lower than the minimum specification through oversampling, use the CDR in LTR mode only.

Symbol	Parameter	Condition	Min	Typ	Max	Unit
t_{OUTPJ_DC}[67]	Period jitter for dedicated clock output in integer PLL	$F_{OUT} \geq 100$ MHz	—	—	175	ps (p-p)
		$F_{OUT} < 100$ MHz	—	—	17.5	mUI (p-p)
t_{FOUTPJ_DC}[67]	Period jitter for dedicated clock output in fractional PLL	$F_{OUT} \geq 100$ MHz	—	—	250[68], 175[69]	ps (p-p)
		$F_{OUT} < 100$ MHz	—	—	25[68], 17.5[69]	mUI (p-p)
t_{OUTCCJ_DC}[67]	Cycle-to-cycle jitter for dedicated clock output in integer PLL	$F_{OUT} \geq 100$ MHz	—	—	175	ps (p-p)
		$F_{OUT} < 100$ MHz	—	—	17.5	mUI (p-p)
$t_{FOUTCCJ\_DC}$[67]	Cycle-to-cycle jitter for dedicated clock output in fractional PLL	$F_{OUT} \geq 100$ MHz	—	—	250[68], 175[69]	ps (p-p)
		$F_{OUT} < 100$ MHz	—	—	25[68], 17.5[69]	mUI (p-p)
t_{OUTPJ_IO}[67][70]	Period jitter for clock output on a regular I/O in integer PLL	$F_{OUT} \geq 100$ MHz	—	—	600	ps (p-p)
		$F_{OUT} < 100$ MHz	—	—	60	mUI (p-p)
t_{FOUTPJ_IO}[67][68][70]	Period jitter for clock output on a regular I/O in fractional PLL	$F_{OUT} \geq 100$ MHz	—	—	600	ps (p-p)
		$F_{OUT} < 100$ MHz	—	—	60	mUI (p-p)
t_{OUTCCJ_IO}[67][70]	Cycle-to-cycle jitter for clock output on a regular I/O in integer PLL	$F_{OUT} \geq 100$ MHz	—	—	600	ps (p-p)
		$F_{OUT} < 100$ MHz	—	—	60	mUI (p-p)
$t_{FOUTCCJ\_IO}$[67][68][70]	Cycle-to-cycle jitter for clock output on a regular I/O in fractional PLL	$F_{OUT} \geq 100$ MHz	—	—	600	ps (p-p)
		$F_{OUT} < 100$ MHz	—	—	60	mUI (p-p)

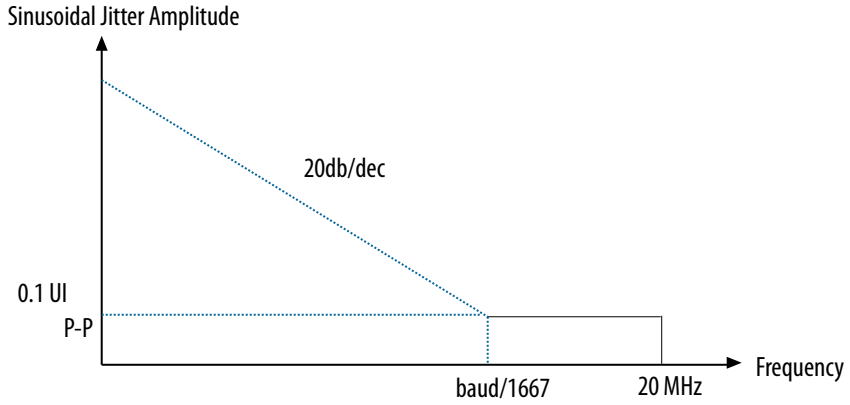
(67) Peak-to-peak jitter with a probability level of 10^{-12} (14 sigma, 99.99999999974404% confidence level). The output jitter specification applies to the intrinsic jitter of the PLL, when an input jitter of 30 ps is applied. The external memory interface clock output jitter specifications use a different measurement method and are available in Memory Output Clock Jitter Specification for Arria V Devices table.

(68) This specification only covered fractional PLL for low bandwidth. The f_{VCO} for fractional value range 0.05–0.95 must be ≥ 1000 MHz.

(69) This specification only covered fractional PLL for low bandwidth. The f_{VCO} for fractional value range 0.20–0.80 must be ≥ 1200 MHz.

(70) External memory interface clock output jitter specifications use a different measurement method, which are available in Memory Output Clock Jitter Specification for Arria V Devices table.

Figure 1-6: LVDS Soft-CDR/DPA Sinusoidal Jitter Tolerance Specification for a Data Rate Less than 1.25 Gbps



DLL Frequency Range Specifications

Table 1-43: DLL Frequency Range Specifications for Arria V Devices

Parameter	–I3, –C4	–I5, –C5	–C6	Unit
DLL operating frequency range	200 – 667	200 – 667	200 – 667	MHz

DQS Logic Block Specifications

Table 1-44: DQS Phase Shift Error Specifications for DLL-Delayed Clock (t_{DQS_PSERR}) for Arria V Devices

This error specification is the absolute maximum and minimum error.

Number of DQS Delay Buffer	–I3, –C4	–I5, –C5	–C6	Unit
2	40	80	80	ps

Table 1-57: RGMII RX Timing Requirements for Arria V Devices

Symbol	Description	Min	Typ	Unit
T_{clk} (1000Base-T)	RX_CLK clock period	—	8	ns
T_{clk} (100Base-T)	RX_CLK clock period	—	40	ns
T_{clk} (10Base-T)	RX_CLK clock period	—	400	ns
T_{su}	RX_D/RX_CTL setup time	1	—	ns
T_h	RX_D/RX_CTL hold time	1	—	ns

Figure 1-14: RGMII RX Timing Diagram

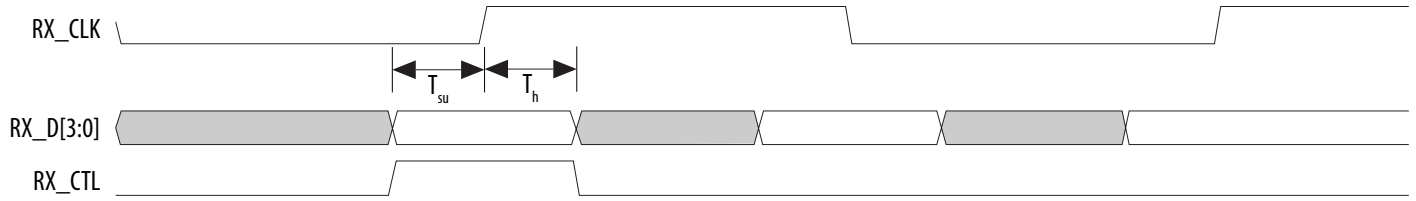
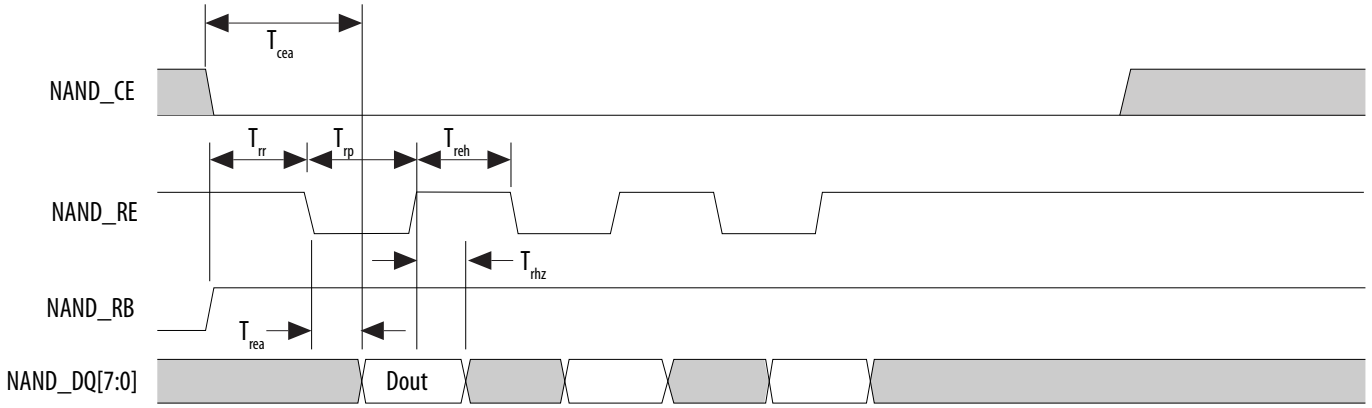


Table 1-58: Management Data Input/Output (MDIO) Timing Requirements for Arria V Devices

Symbol	Description	Min	Typ	Max	Unit
T_{clk}	MDC clock period	—	400	—	ns
T_d	MDC to MDIO output data delay	10	—	20	ns
T_s	Setup time for MDIO data	10	—	—	ns
T_h	Hold time for MDIO data	0	—	—	ns

Figure 1-20: NAND Data Read Timing Diagram



ARM Trace Timing Characteristics

Table 1-61: ARM Trace Timing Requirements for Arria V Devices

Most debugging tools have a mechanism to adjust the capture point of trace data.

Description	Min	Max	Unit
CLK clock period	12.5	—	ns
CLK maximum duty cycle	45	55	%
CLK to D0 –D7 output data delay	–1	1	ns

UART Interface

The maximum UART baud rate is 6.25 megasymbols per second.

GPIO Interface

The minimum detectable general-purpose I/O (GPIO) pulse width is 2 µs. The pulse width is based on a debounce clock frequency of 1 MHz.

Date	Version	Changes

December 2015	2015.12.16	• Updated Quad Serial Peripheral Interface (SPI) Flash Timing Requirements for Arria V Devices table.
		  • Updated F_{clk}, $T_{dutycycle}$, and $T_{dssfrst}$ specifications.
		  • Added T_{qspi_clk}, T_{din_start}, and T_{din_end} specifications.
		  • Removed T_{dinmax} specifications.
		• Updated the minimum specification for T_{clk} to 16.67 ns and removed the maximum specification in SPI Master Timing Requirements for Arria V Devices table.
		• Updated Secure Digital (SD)/MultiMediaCard (MMC) Timing Requirements for Arria V Devices table.
		  • Updated T_{clk} to $T_{sdmmc\_clk\_out}$ symbol.
		  • Updated $T_{sdmmc\_clk\_out}$ and T_{d} specifications.
		  • Added T_{sdmmc_clk}, T_{su}, and T_{h} specifications.
		  • Removed T_{dinmax} specifications.
		• Updated the following diagrams:
		  • Quad SPI Flash Timing Diagram
		  • SD/MMC Timing Diagram
		• Updated configuration .rbf sizes for Arria V devices.
		• Changed instances of *Quartus II* to *Quartus Prime*.

Symbol	Description	V_{CCIO} (V)	Typical	Unit
dR/dV	OCT variation with voltage without re-calibration	3.0	0.0297	%/mV
		2.5	0.0344	
		1.8	0.0499	
		1.5	0.0744	
		1.2	0.1241	
dR/dT	OCT variation with temperature without re-calibration	3.0	0.189	%/°C
		2.5	0.208	
		1.8	0.266	
		1.5	0.273	
		1.2	0.317	

Pin Capacitance

Table 2-13: Pin Capacitance for Arria V GZ Devices

Symbol	Description	Maximum	Unit
C_{IOTB}	Input capacitance on the top and bottom I/O pins	6	pF
C_{IOLR}	Input capacitance on the left and right I/O pins	6	pF
C_{OUTFB}	Input capacitance on dual-purpose clock output and feedback pins	6	pF

Hot Socketing

Table 2-14: Hot Socketing Specifications for Arria V GZ Devices

Symbol	Description	Maximum
$I_{IOPIN\ (DC)}$	DC current per I/O pin	300 µA
$I_{IOPIN\ (AC)}$	AC current per I/O pin	8 mA (124)
$I_{XCVR\text{-}TX\ (DC)}$	DC current per transceiver transmitter pin	100 mA
$I_{XCVR\text{-}RX\ (DC)}$	DC current per transceiver receiver pin	50 mA

Internal Weak Pull-Up Resistor

Table 2-15: Internal Weak Pull-Up Resistor for Arria V GZ Devices

All I/O pins have an option to enable the weak pull-up resistor except the configuration, test, and JTAG pins. The internal weak pull-down feature is only available for the JTAG TCK pin. The typical value for this internal weak pull-down resistor is approximately 25 kΩ .

Symbol	Description	V_{CCIO} Conditions (V) (125)	Value (126)	Unit
R_{PU}	Value of the I/O pin pull-up resistor before and during configuration, as well as user mode if you enable the programmable pull-up resistor option.	3.0 ±5%	25	k Ω
		2.5 ±5%	25	k Ω
		1.8 ±5%	25	k Ω
		1.5 ±5%	25	kΩ
		1.35 ±5%	25	k Ω
		1.25 ±5%	25	k Ω
		1.2 ±5%	25	k Ω

(124) The I/O ramp rate is 10 ns or more. For ramp rates faster than 10 ns, $|I_{IOPIN}| = C\ dv/dt$, in which C is the I/O pin capacitance and dv/dt is the slew rate.
(125) The pin pull-up resistance values may be lower if an external source drives the pin higher than V_{CCIO}.
(126) These specifications are valid with a ±10% tolerance to cover changes over PVT.

Figure 2-4: LVDS Soft-CDR/DPA Sinusoidal Jitter Tolerance Specification for a Data Rate ≥ 1.25 Gbps

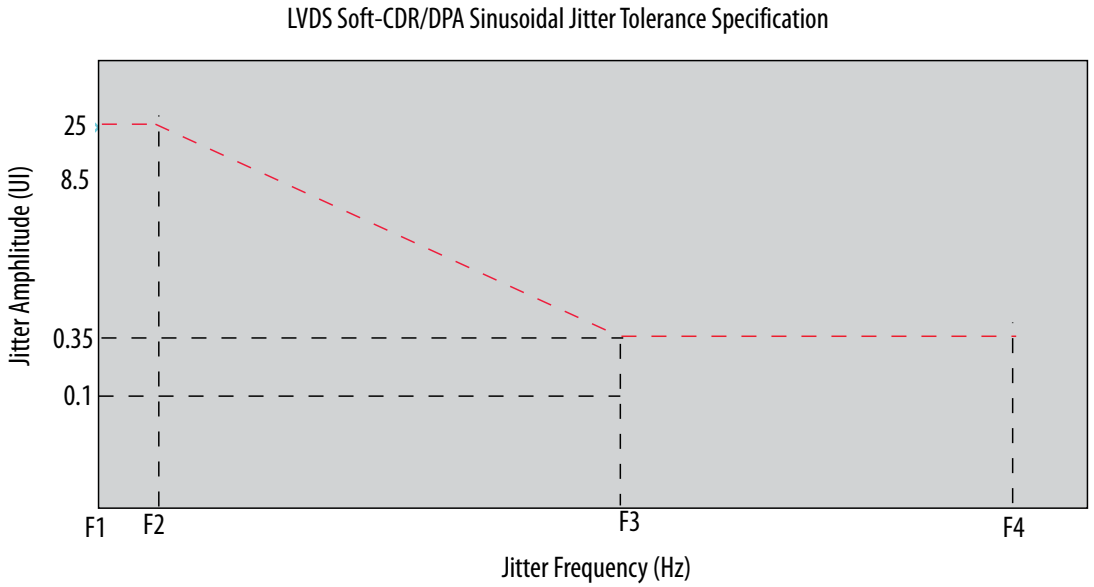


Table 2-45: LVDS Soft-CDR/DPA Sinusoidal Jitter Mask Values for a Data Rate ≥ 1.25 Gbps

Jitter Frequency (Hz)		Sinusoidal Jitter (UI)
F1	10,000	25.000
F2	17,565	25.000
F3	1,493,000	0.350
F4	50,000,000	0.350

Symbol	Parameter	Minimum	Maximum	Unit
t_{CD2CU}	CONF_DONE high to CLKUSR enabled	4 × maximum DCLK period	—	—
t_{CD2UMC}	CONF_DONE high to user mode with CLKUSR option on	t_{CD2CU} + (8576 × CLKUSR period) (209)	—	—

Related Information

- **DCLK-to-DATA[] Ratio (r) for FPP Configuration** on page 2-57
- **Configuration, Design Security, and Remote System Upgrades in Arria V Devices**

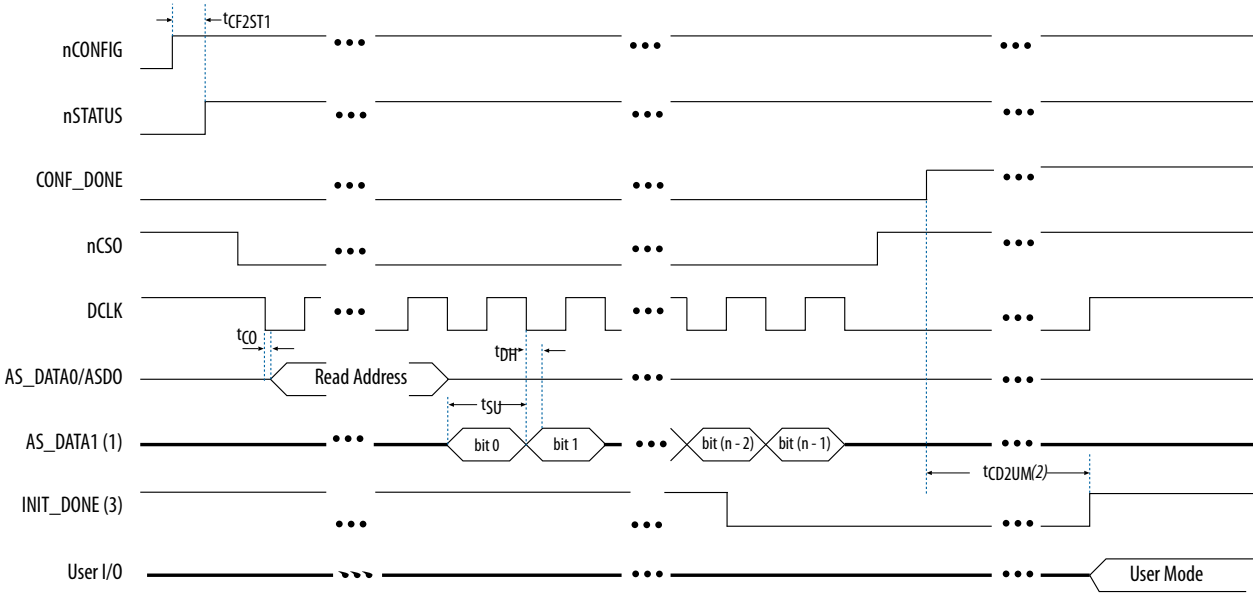
(208) The minimum and maximum numbers apply only if you chose the internal oscillator as the clock source for initializing the device.

(209) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the "Initialization" section of the *Configuration, Design Security, and Remote System Upgrades in Arria V Devices* chapter.

Active Serial Configuration Timing

Figure 2-9: AS Configuration Timing

Timing waveform for the active serial (AS) x1 mode and AS x4 mode configuration timing.



Notes:
1. If you are using AS ×4 mode, this signal represents the AS_DATA[3..0] and EPCQ sends in 4-bits of data for each DCLK cycle.
2. The initialization clock can be from internal oscillator or CLKUSR pin.
3. After the option bit to enable the INIT_DONE pin is configured into the device, the INIT_DONE goes low.

Table 2-58: AS Timing Parameters for AS x1 and AS x4 Configurations in Arria V GZ Devices

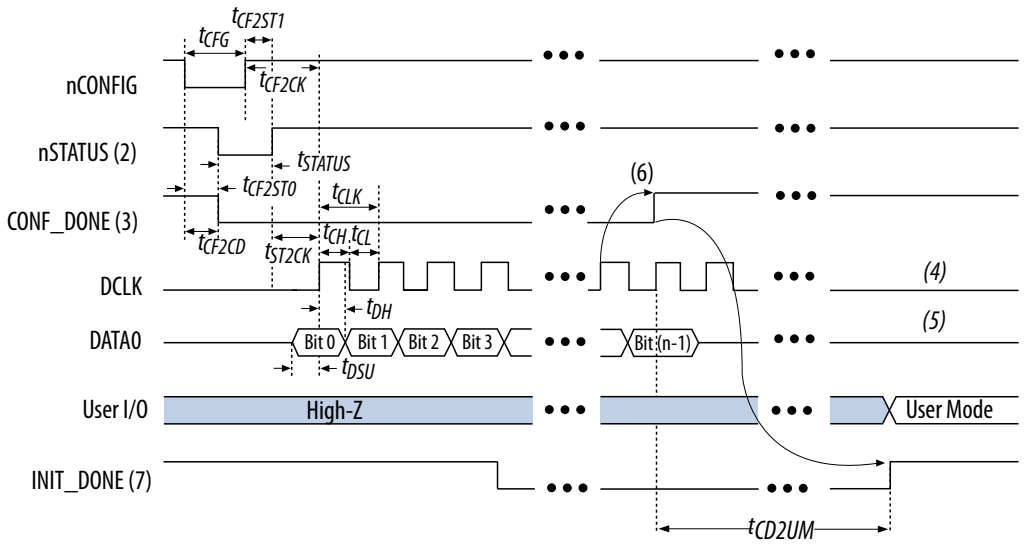
The minimum and maximum numbers apply only if you choose the internal oscillator as the clock source for initializing the device.

t_{CF2CD}, t_{CF2ST0}, t_{CFG}, t_{STATUS}, and t_{CF2ST1} timing parameters are identical to the timing parameters for PS mode listed in the "PS Timing Parameters for Arria V GZ Devices" table.

Passive Serial Configuration Timing

Figure 2-10: PS Configuration Timing Waveform

Timing waveform for a passive serial (PS) configuration when using a MAX II device, MAX V device, or microprocessor as an external host.



Notes:

1. The beginning of this waveform shows the device in user mode. In user mode, nCONFIG, nSTATUS, and CONF_DONE are at logic high levels. When nCONFIG is pulled low, a reconfiguration cycle begins.
2. After power-up, the Arria V GZ device holds nSTATUS low for the time of the POR delay.
3. After power-up, before and during configuration, CONF_DONE is low.
4. Do not leave DCLK floating after configuration. DCLK is ignored after configuration is complete. It can toggle high or low if required.
5. DATA0 is available as a user I/O pin after configuration. The state of this pin depends on the dual-purpose pin settings in the Device and Pins Option.
6. To ensure a successful configuration, send the entire configuration data to the Arria V GZ device. CONF_DONE is released high after the Arria V GZ device receives all the configuration data successfully. After CONF_DONE goes high, send two additional falling edges on DCLK to begin initialization and enter user mode.
7. After the option bit to enable the INIT_DONE pin is configured into the device, the INIT_DONE goes low.

Programmable IOE Delay

Table 2-66: IOE Programmable Delay for Arria V GZ Devices

Parameter [228]	Available Settings	Min Offset [229]	Fast Model		Slow Model				Unit
			Industrial	Commercial	C3	C4	I3L	I4	
D1	64	0	0.464	0.493	0.924	1.011	0.921	1.006	ns
D2	32	0	0.230	0.244	0.459	0.503	0.456	0.500	ns
D3	8	0	1.587	1.699	2.992	3.192	3.047	3.257	ns
D4	64	0	0.464	0.492	0.924	1.011	0.920	1.006	ns
D5	64	0	0.464	0.493	0.924	1.011	0.921	1.006	ns
D6	32	0	0.229	0.244	0.458	0.503	0.456	0.499	ns

Programmable Output Buffer Delay

Table 2-67: Programmable Output Buffer Delay for Arria V GZ Devices

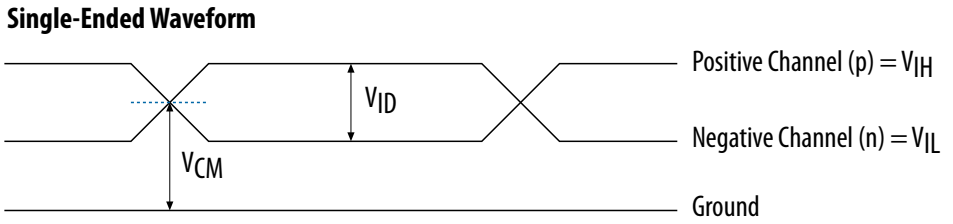
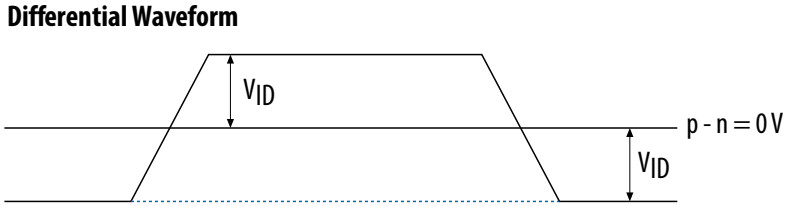
You can set the programmable output buffer delay in the Quartus II software by setting the **Output Buffer Delay Control** assignment to either positive, negative, or both edges, with the specific values stated here (in ps) for the **Output Buffer Delay** assignment.

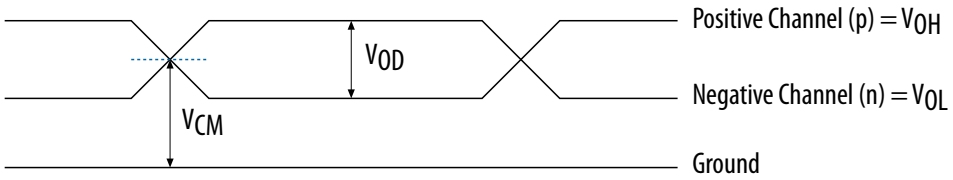
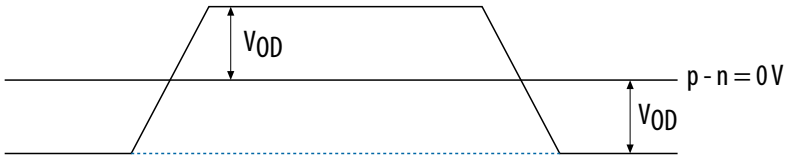
Symbol	Parameter	Typical	Unit
D_{OUTBUF}	Rising and/or falling edge delay	0 (default)	ps
		50	ps
		100	ps
		150	ps

(228) You can set this value in the Quartus II software by selecting **D1**, **D2**, **D3**, **D4**, **D5**, and **D6** in the **Assignment Name** column of **Assignment Editor**.
(229) Minimum offset does not include the intrinsic delay.

Glossary

Table 2-68: Glossary

Term	Definition
Differential I/O Standards	Receiver Input Waveforms   Transmitter Output Waveforms

Term	Definition
	Single-Ended Waveform  **Differential Waveform** 
f_{HSCLK}	Left and right PLL input clock frequency.
f_{HSDR}	High-speed I/O block—Maximum and minimum LVDS data transfer rate (f_{HSDR} = 1/TUI), non-DPA.
$f_{HSDRDPA}$	High-speed I/O block—Maximum and minimum LVDS data transfer rate ($f_{HSDRDPA}$ = 1/TUI), DPA.
J	High-speed I/O block—Deserialization factor (width of parallel data bus).